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APR 12 2002

PTO/SB/08 (2-92)
Sheet 1 of 2

Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>		Docket Number 509982000100	Application Number 09/770,997
		Applicant	Xinhui NIU and Nickhil JAKATDAR
		Filing Date January 25, 2001	Group Art Unit 2621 2877
		Mailing Date April 9, 2002	

U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
QW	1.	7/21/92	5,131,752	Yu et al.			
QW	2.	11/17/92	5,164,790	McNeil et al.			
QW	3.	3/4/97	5,607,800	Ziger			RECEIVED
QW	4.	4/14/98	5,739,909	Blayo et al.			
QW	5.	11/10/98	5,835,225	Thakur			APR 17 2002
QW	6.	2/2/99	5,867,276	McNeil et al.			Technology Center 2600
QW	7.	10/5/99	5,963,329	Conrad et al.			

FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
QW	8.	N. W. Ashcroft et al., "Solid State Physics", Saunders College Philadelphia, 1976, pgs. 133-135.
QW	9.	R. M. A. Azzam et al., "Ellipsometry and Polarized Light", Elsevier Science B. V., 1987, book.
QW	10.	Ch. M. Bishop, "Neural Networks for Pattern Recognition", Ch. 4, 1995, pp. 117-161.
QW	11.	S. Bushman et al., "Scatterometry Measurements for Process Monitoring of Gate Etch", AEC/APC Workshop IX, Sematech, Sept. 20-24, 1997, pp. 148-158.
QW	12.	G. Granet et al., "Efficient implementation of the coupled-wave method for metallic lamellar in TM polarization", J. Opt. Soc. Am. vol. 13, no. 5, May 1996, pp. 1019-1023.
QW	13.	O. S. Heavens, "Optical Properties of Thin Solid Films", Dover Publications, Inc. 1955, book.
QW	14.	P. Lalanne et al., "Highly improved convergence of the coupled-wave method for TM polarization", J. Opt. Soc. Am. vol. 13, no. 4, April 1996, pp. 779-784.
QW	15.	L. Li et al., "Convergence of the coupled-wave method for metallic lamellar diffraction gratings", J. Opt. Soc. Am. vol. 10, no. 6, June 1993, pp. 1184-1189.

EXAMINER:

DATE CONSIDERED:

27 July 2004

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.



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QW	16.	D. Maystre, "A new general integral theory for dielectric coated gratings", J. of Opt. Soc. of Amer. vol. 68 (4), Apr. 78, pp. 189-194.
QW	17.	M. G. Moharam et al., "Rigorous coupled-wave analysis of planar-grating diffraction", J. Opt. Soc. Am. vol. 71, no. 7/July 1981, pp. 811-818.
QW	18.	M. G. Moharam et al., "Formulation for stable and efficient implementation of the rigorous coupled-wave analysis of binary gratings", J. Opt. Soc. Am. vol. 12, no. 5, May 1995, pp. 1068-1076.
QW	19.	Moharam et al., "Stable implementation of the rigorous coupled-wave analysis for surface - relief gratings: enhanced transmittance matrix approach", J. Opt. Soc. Am. vol. 12, no. 5, May 1995, pp. 1077-1086.
QW	20.	M. Neviere et al., "Systematic Study of Resonances of Holographic Thin Film Couplers", Optics Com. vol. 9 (1), 1973, pp. 205-209.
QW	21.	A. R. Neureuther et al., "Numerical Methods for the Analysis of Scattering from Nonplanar Periodic Structures", URSI Symposium on Electromag. Waves, 1969, pp. 185-188.
QW	22.	W. H. Press et al., "Numerical Recipes in C", Art of Scien. Computing 2nd Ed., 1986, pp. 29-38.
QW	23.	J. A. Rice, "Mathematical Statistics and Data Analysis" sec. ed., ch. 14, Duxbury Press, 1995, pp. 507-570.

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